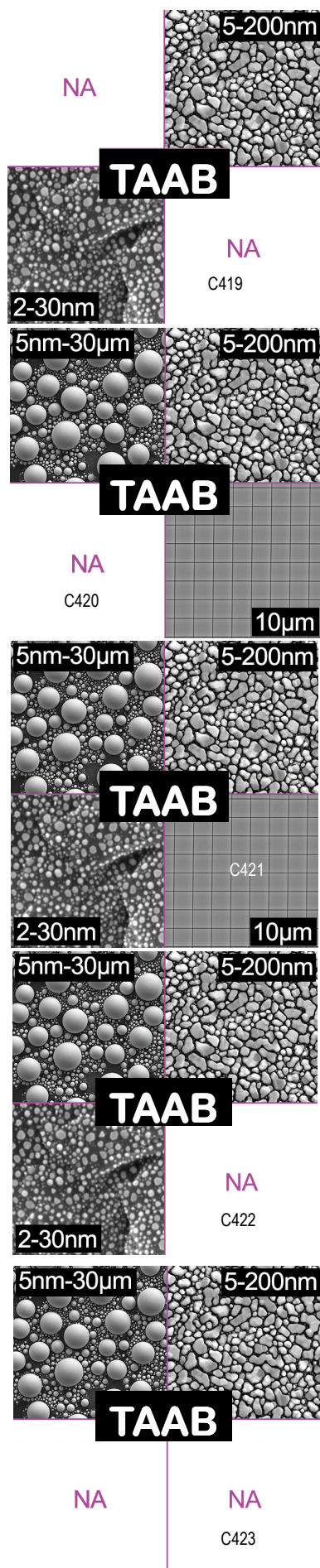


## SEM Multi &amp; Combination Test Standards



**Gold on Carbon** resolution standards with their varying sized gaps between gold crystals on a carbon substrate allow tests for resolution, as well as checking the quality of grey-level reproduction at high resolution. **Tin on Carbon** resolution standard is good for astigmatism and image shift measurements for SEMs. The **Ruled Silicon Grid** is excellent for comparing magnification and assessing distortion in the image field.

**Gold and Hi Res Gold on Carbon**

C419/P	Dual standard <b>gold &amp; Hi Res gold</b> on <b>carbon</b>	12.5mm Ø pin stub
C419/H	Dual standard <b>gold &amp; Hi Res gold</b> on <b>carbon</b>	15mm Ø Hitachi Stub
C419/J	Dual standard <b>gold &amp; Hi Res gold</b> on <b>carbon</b>	10mm Ø JEOL Stub

**Tin and Gold on Carbon with Ruled Silicon**

C420/P	Triple standard <b>Tin &amp; gold on carbon &amp; ruled silicon</b>	12.5mm Ø pin stub
C420/H	Triple standard <b>Tin &amp; gold on carbon &amp; ruled silicon</b>	15mm Ø Hitachi stub
C420/J	Triple standard <b>Tin &amp; gold on carbon &amp; ruled silicon</b>	10mm Ø JEOL stub

**Tin, Gold and Hi Res Gold on Carbon with Ruled Silicon**

C421P	Multi standard <b>Tin, Gold, &amp; Hi Res Gold</b> on <b>carbon</b> and <b>ruled Silicon</b>	12.5mm Ø pin stub on
C421/H	Multi standard <b>Tin, Gold &amp; Hi Res Gold</b> on <b>carbon</b> and <b>ruled Silicon</b>	15mm Ø Hitachi stub
C421/J	Multi standard <b>Tin, Gold &amp; Hi Res Gold</b> on <b>carbon</b> and <b>ruled Silicon</b>	10mm Ø JEOL stub

**Tin, Gold and Hi Res Gold on Carbon**

C422/P	Triple standard <b>Tin, Gold &amp; Hi Res Gold</b> on <b>carbon</b>	12.5mm Ø pin stub
C422/H	Triple standard <b>Tin, Gold &amp; Hi Res Gold</b> on <b>carbon</b>	15mm Ø Hitachi stub
C422/J	Triple standard <b>Tin, Gold &amp; Hi Res Gold</b> on <b>carbon</b>	10mm Ø JEOL stub

**Tin and Gold on Carbon**

C423/P	Dual standard <b>Tin &amp; Gold</b> on <b>carbon</b>	12.5mm Ø pin stub
C423/H	Dual standard <b>Tin &amp; Gold</b> on <b>carbon</b>	15mm Ø Hitachi stub
C423/J	Dual standard <b>Tin &amp; Gold</b> on <b>carbon</b>	10mm Ø JEOL stub

## SEM Combination Test Standards cont.

Tin on Ruled Silicon

Magnification and Resolution Standard

C424/P Dual standard Tin on Silicon resolution

12.5mm pin stub

C424/H Dual standard Tin on Silicon resolution

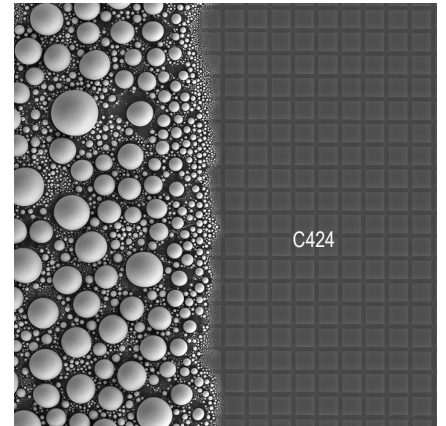
15mm Hitachi stub

C424/J Dual standard Tin on Silicon resolution

10mm JEOL stub

C424 Dual standard Tin on Silicon resolution

unmounted



Save time effort and money by using our SEM Multiple Combination Standards where you can move immediately from one standard to the next. **Ideal for Benchtop SEMs.**

**All combination standards can be mounted on a stub of your choice to special order**